

# Forward Modeling Chromatic Aberration and Depth of Field in Transmission X-ray Microscopy

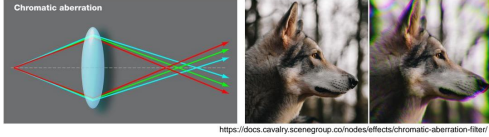
Zane Taylor

Stanford University, EE367, Winter 2024

## Motivation

Transmission X-ray Microscopy (TXM) is a powerful technique for operando studies of dynamical systems, including laser powder bed fusion (LPBF) metal additive manufacturing.

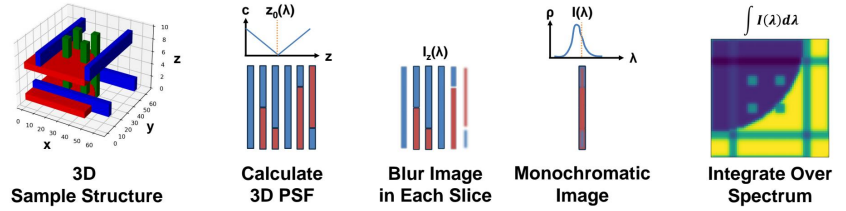
X-ray lenses tend to be highly chromatic



Goal: Implement a simple method to predict image formation

- Chromatic Aberration
- Depth of Field Blurring

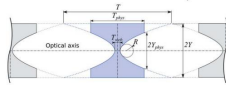
## Present Technique



- This work is computationally cheap & tied to the physics of x-ray lenses  
Defocus blur is computed for each energy independently and then the effect is summed, giving the contribution of each energy
- Related work calculates the chromatic PSF of the lens independent of defocusing
- Wave-optics simulations such as multi-slice models are a more intensive alternative

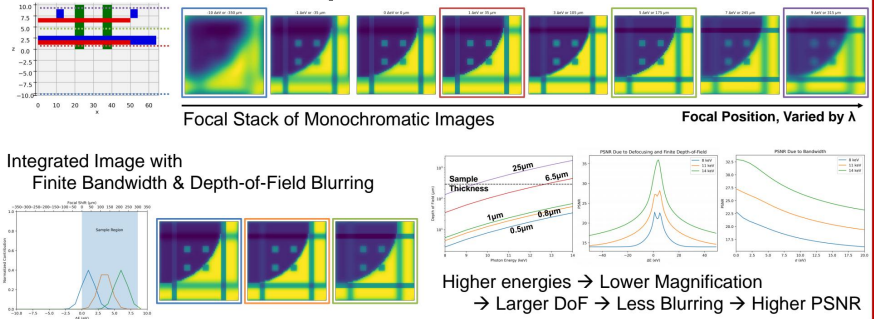
## Related Work

Simons [1] derived the performance of compound refractive lenses (CRLs) used in TXM as well as the chromatic PSF, but this PSF is not energy resolving.



In x-ray imaging, the chromatic aberrations are almost always minimized by beam monochromatization with little further consideration. The optical community models combined defocus- and chromatic aberration in more detail [2].

## Experimental Results



## References

- [1] Simons et al., "Simulating and optimizing compound refractive lens-based X-ray microscopes", J. Synch. Rad., 2016
- [2] Strasburger et al., "Blur Unblurred – A Mini Tutorial", i-Perception, 2018